

**Список основных публикаций по теме диссертации
в рецензируемых научных изданиях за последние 5 лет:**

1. Scherbinin D.P., Konshina E.A., Polischuk V.A. Influence of Surface Properties on the Structure of Granular Silver Films and Excitation of Localized Plasmons // Optics and spectroscopy - 2016, Vol. 120, No. 4, pp. 622–627.
2. Leonov N.B., Gladskikh I.A., Polishchuk V.A., Vartanyan T.A. Evolution of the optical properties and morphology of thin metal films during growth and annealing // Optics and spectroscopy - 2015, Vol. 119, No. 3, pp. 450-455.
3. Tomaev V.V., Karasev V.Y., Polishchuk V.A. Electron-stimulated desorption of the surface of mechanically modified silver-iodide particles // Journal of Surface Investigation. X-ray, Synchrotron and Neutron Techniques - 2015, Vol. 9, No. 6, pp. 1172–1177.
4. Polischuk V.A., Tomaev V.V., Baranov A.V. Growth of metallic Ag whisker single crystals on AgI films // Technical Physics - 2014, Vol. 59, No. 10, pp. 1476-148.
5. Tomaev, V. V, Polishchuk, V. A., Karasev, V. Yu. Modification of silver iodide particles caused by a flow of electrons // Glass Physics and Chemistry, 2014. —Vol. 40. —No. 4. —pp. 453-456.
6. Polischuk V.A., Tomaev V.V., Baranov A.V. Growth of metallic Ag whisker single crystals on AgI films. //Technical Physics, 2014. —Vol. 59. —No. 10. — pp. 1476-1481.
7. Alipieva E., Zlatov A S., Polischuk V.A., Briukhovetskiy A.P, Grigoriev D.E. Influence of quantum dots size dispersion on the fluorescence spectrum // Proceedings of SPIE, 2013. — Vol. 8770.— pp. 87700T.
8. Анисимова Г. П., Долматова О. А., Полищук В. А., Цыганкова Г. А. Полуэмпирический расчёт параметров тонкой структуры, коэффициентов промежуточной связи и гирромагнитных отношений конфигураций $\text{npn}'f \text{ C I, Si I, Ge I и P II}$ // Вестник СПбГУ, 2013 — Серия 4. —№1. — С.215-227.
9. Baranov A.V., Cherevko S.A., Polischuk V.A., Slavov D., Petrov L., Todorov G. Fluorescence from $\text{Pb}_{1-x}\text{Cd}_x\text{Se}$ polycrystalline films excited by non-monochromatic light at $\lambda_{\text{max}} = 0.9 \mu\text{m}$. Proceedings of SPIE, 2011.—Vol. 7747. — pp. 774707.